


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/674,479	YOON, WAN HYUK	
	Examiner	Art Unit	
	Anish Desai	1771	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor search using PALM	9/19/2005	APD
Inventor search using EAST	9/26/2005	APD
428/141156,167,172,179,181 (Text search only-see EAST search history printout)	9/26/2005	APD
428/63,424.2,66.5 (Text search only-see EAST search history printout)	9/26/2005	APD
383/105,109,116 (Text search only-see EAST search history printout)	9/26/2005	APD
Text search using EAST	9/26/2005	APD